

SuperFET\*\*

# FCP11N60F/FCPF11N60F 600V N-Channel MOSFET

#### **Features**

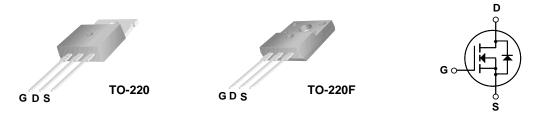
- 650V @T<sub>J</sub> = 150°C
- Typ.  $R_{DS(on)} = 0.32\Omega$
- Fast Recovery Type (t<sub>rr</sub> = 120ns)
- Ultra Low Gate Charge (typ. Q<sub>q</sub> = 40nC)
- Low Effective Output Capacitance (typ. Cosseff.=95pF)
- 100% avalanche tested
- RoHS Compliant



### **Description**

SuperFET<sup>TM</sup> is, Fairchild's proprietary, new generation of high voltage MOSFET family that is utilizing an advanced charge balance mechanism for outstanding low on-resistance and lower gate charge performance.

This advanced technology has been tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy. Consequently, SuperFET is very suitable for various AC/DC power conversion in switching mode operation for system miniaturization and higher efficiency.



### **Absolute Maximum Ratings**

Symbol	Parameter		FCP11N60F FCPF11N60F		Units
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		11	11 *	Α
	- Continuous (T <sub>C</sub> = 100°C)		7 7*		Α
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	33	33 *	Α
V <sub>GSS</sub>	Gate-Source Voltage		± 30		V
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		3	mJ	
I <sub>AR</sub>	Avalanche Current	(Note 1)	11		Α
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		1:	mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4	V/ns	
$P_{D}$	Power Dissipation (T <sub>C</sub> = 25°C)		125	36 *	W
	- Derate above 25°C		1.0	0.29 *	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150		°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300		°C

<sup>\*</sup> Drain current limited by maximum junction termperature.

### **Thermal Characteristics**

Symbol	Parameter	FCP11N60F	FCPF11N60F	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1.0	3.5	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	°C/W

# **Package Marking and Ordering Information**

<b>Device Marking</b>	Device	Package	Reel Size	Tape Width	Quantity
FCP11N60F	FCP11N60F	TO-220			50
FCPF11N60F	FCPF11N60F	TO-220F			50

# **Electrical Characteristics** $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	teristics				1	I
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}, T_J = 25^{\circ}\text{C}$	600			V
		$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}, T_J = 150^{\circ}\text{C}$		650		V
$\Delta BV_{DSS}/$ $\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 μA, Referenced to 25°C		0.6		V/°C
BV <sub>DS</sub>	Drain-Source Avalanche Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 11 A		700		V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V			10	μΑ
		V <sub>DS</sub> = 480 V, T <sub>C</sub> = 125°C			100	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V			-100	nA
On Charac	teristics					1
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	3.0		5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 5.5 \text{ A}$		0.32	0.38	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 5.5 A (Note 4)		9.7		S
Dynamic C	haracteristics					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V,		1148	1490	pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		671	870	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			63	82	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 480 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		35		pF
Coss eff.	Effective Output Capacitance	V <sub>DS</sub> = 0V to 480 V, V <sub>GS</sub> = 0 V		95		pF
Switching	Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 300 V, I <sub>D</sub> = 11 A,		34	80	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		98	205	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			119	250	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)		56	120	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 480 V, I <sub>D</sub> = 11 A,		40	52	nC
Q <sub>gs</sub>	Gate-Source Charge	$V_{GS} = 10 \text{ V}$		7.2		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)		21		nC
Drain-Sour	ce Diode Characteristics and Maximun	n Ratings				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				11	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F	orward Current			33	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 11 A			1.4	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 11 A,		120		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F / dt = 100 \text{ A/}\mu\text{s} $ (Note 4)		0.8		μC

#### Notes

- 1. Repetitive Rating : Pulse width limited by maximum junction temperature
- 2.  $\rm I_{AS}$  = 5.5A,  $\rm V_{DD}$  = 50V,  $\rm R_{G}$  = 25  $\Omega,$  Starting  $\rm ~T_{J}$  = 25°C
- 3.  $I_{SD} \le 11 \, A, \ di/dt \le 200 \, A/\mu s, \ V_{DD} \le BV_{DSS,} \ Starting \ T_J = 25 ^{\circ}C$
- 4. Pulse Test : Pulse width  $\leq 300 \mu s,$  Duty cycle  $\leq 2\%$
- 5. Essentially independent of operating temperature

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

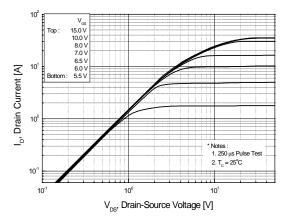


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

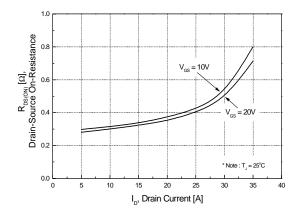


Figure 5. Capacitance Characteristics

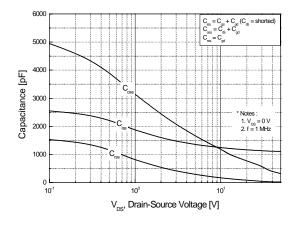


Figure 2. Transfer Characteristics

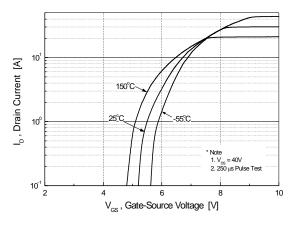


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

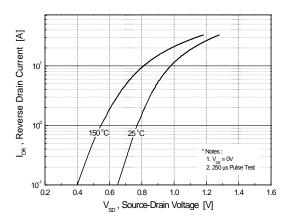
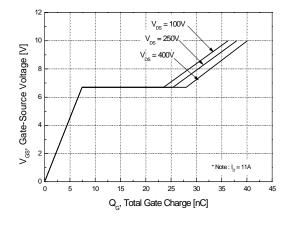


Figure 6. Gate Charge Characteristics



### **Typical Performance Characteristics (Continued)**

Figure 7. Breakdown Voltage Variation vs. Temperature

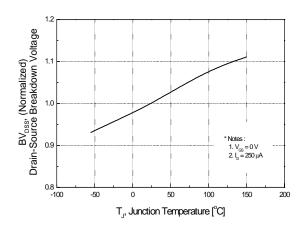


Figure 8. On-Resistance Variation vs. Temperature

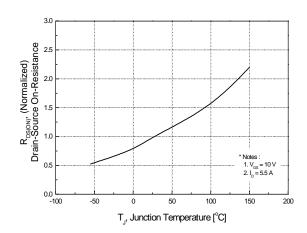


Figure 9-1. Safe Operating Area for FCP11N60F

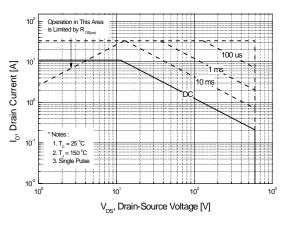


Figure 9-2. Safe Operating Area for FCPF11N60F

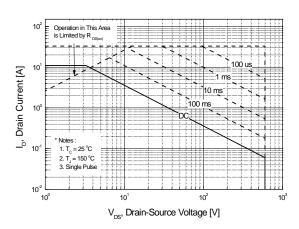
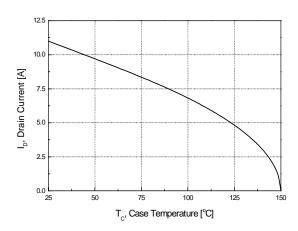


Figure 10. Maximum Drain Current vs. Case Temperature



# **Typical Performance Characteristics (Continued)**

Figure 11-1. Transient Thermal Response Curve for FCP11N60F

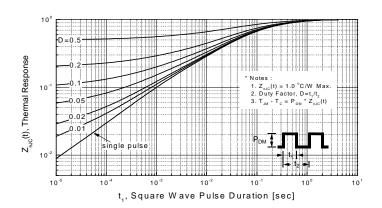
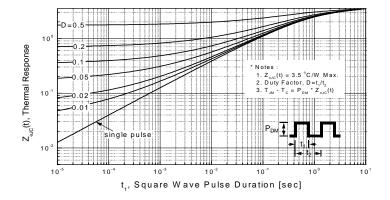
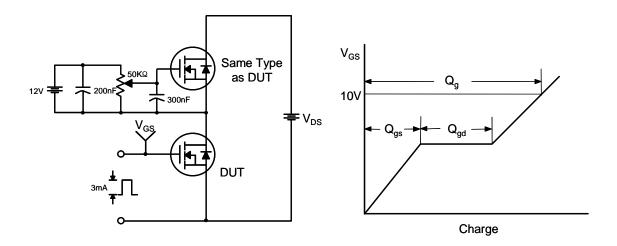


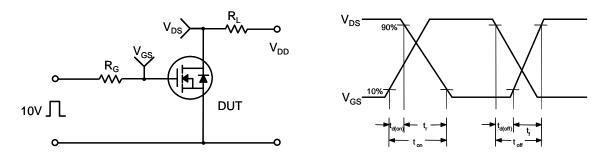
Figure 11-2. Transient Thermal Response Curve for FCPF11N60F



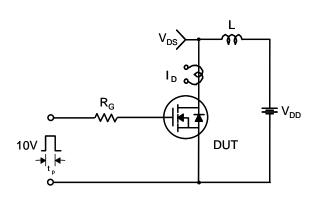
### **Gate Charge Test Circuit & Waveform**

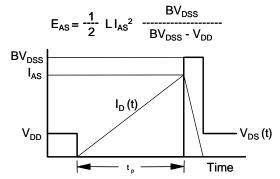


### **Resistive Switching Test Circuit & Waveforms**

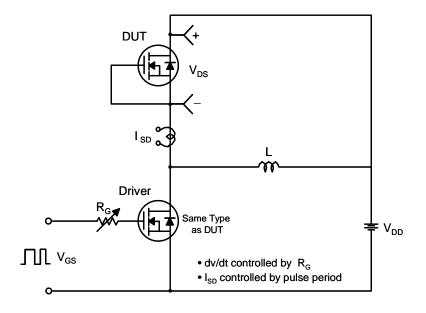


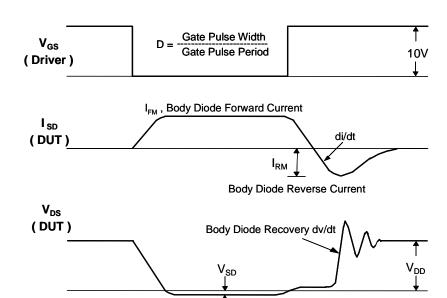
### **Unclamped Inductive Switching Test Circuit & Waveforms**





### Peak Diode Recovery dv/dt Test Circuit & Waveforms

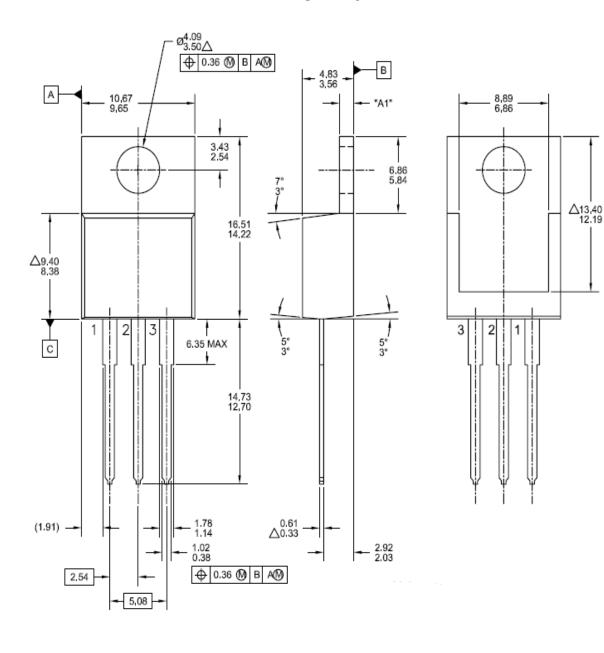


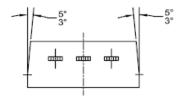


Body Diode Forward Voltage Drop

### **Mechanical Dimensions**

TO - 220

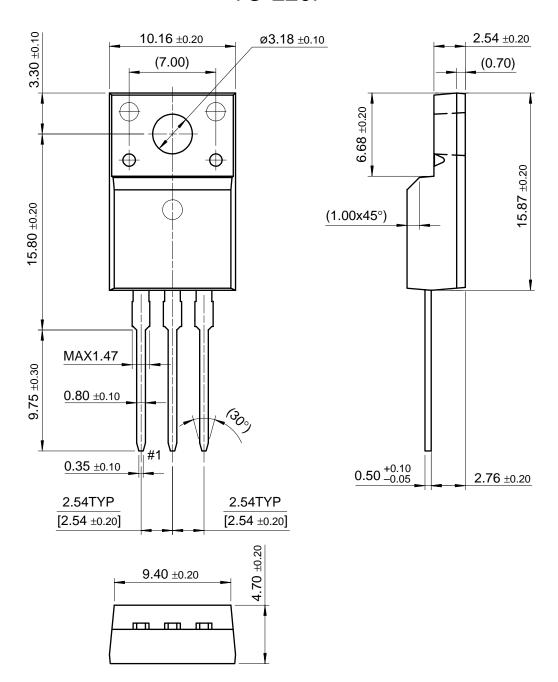




Dimensions in Millimeters

### Mechanical Dimensions (Continued)

**TO-220F** 



Dimensions in Millimeters





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